

650V, 70mΩ typ., Gallium Nitride (GaN) FET in TOLL Package

1. General Description

The HG65C1R070T is a 650V, 70 mΩ Gallium Nitride (GaN) FET in a TOLL package. It is a normally -off device that combines asiasemitech latest high-voltage GaN HEMT with a low voltage silicon MOSFET to offer superior reliability and performance.

2. Features and Benefits

- JEDEC-qualified GaN technology
- Dynamic $R_{DS(on)eff}$ production tested
- Wide gate safety margin
- Capable of reverse conduction
- Low gate charge
- RoHS compliant and Halogen-free packaging
- Achieves increased efficiency in both hard- and soft- switched circuits
 - Increased power density
 - Reduced system size and weight
 - Overall lower system cost
- Easy to drive with commonly-used gate drivers

3. Applications

- Fast charger
- Telecom power
- Data center
- Lighting

4. Key Specifications

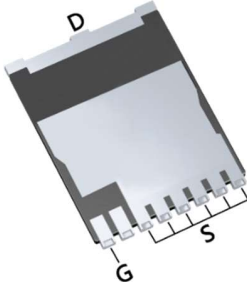
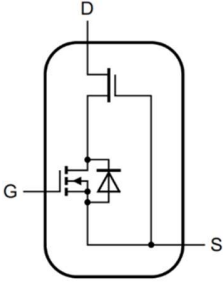
Table 1. Key Specifications

Symbol	Parameter	Value	Unit
$V_{DS, max}$	Drain-source voltage	650	V
$I_{D, max}$	Continuous drain current @Tc = 25°C	22	A
$R_{DS(on), typ}$	Drain-source on-state resistance	70	mΩ
Q_G, typ	Total gate charge	15	nC
$Q_{RR, typ}$	Reverse recovered charge	110	nC

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5. Pin Description

Table 2. Pin Description

Pin	Description	Bottom View	Graphic Symbol
G	Gate		
D	Drain		
S	Source		

6. Ordering Information

Table 3. Ordering Information

Part number	Package	Marking Code
HG65C1R070T	TOLL	HG65C1R070T

7. Absolute Maximum Ratings

Table 4. Absolute Maximum Ratings (Tc=25℃ unless otherwise stated)

Parameter	Symbol	Min.	Max.	Unit.	Conditions
Drain to source voltage	V _{DSS}	650	-	V	V _{GS} = 0V
Transient drain to source voltage	V _{DSS(TR)}	-	800		Non-repetitive Pulse for ≤ 10ms at 25℃
Gate to source voltage	V _{GSS}	-20	20		
Maximum power dissipation	P _D	-	74	W	T _C = 25℃, Fig.1
Continuous drain current	I _D	-	22	A	T _C = 25℃
		-	14	A	T _C = 100℃
Pulsed drain current	I _{DM}	-	128	A	Pulsed, t _p ≤ 100μs, T _C = 25℃
Operating temperature	T _J	-55	150	℃	
Storage temperature	T _S	-55	150	℃	

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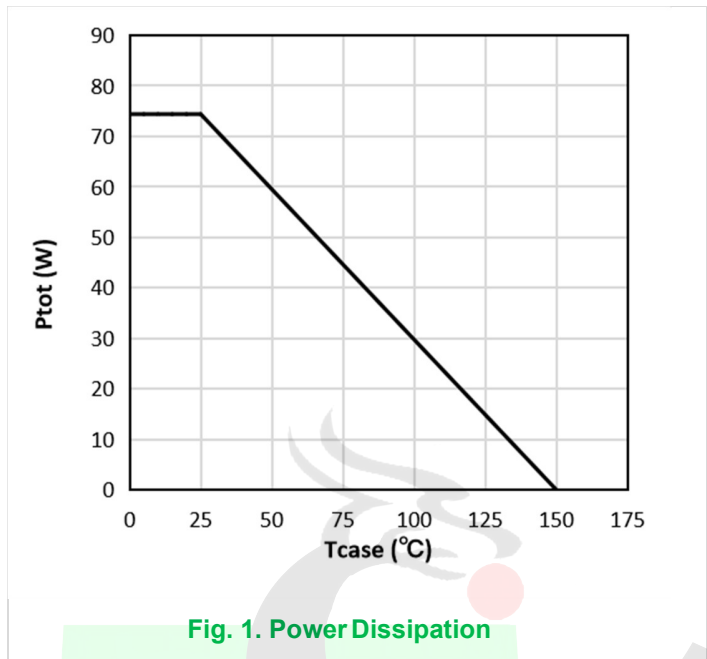


Fig. 1. Power Dissipation

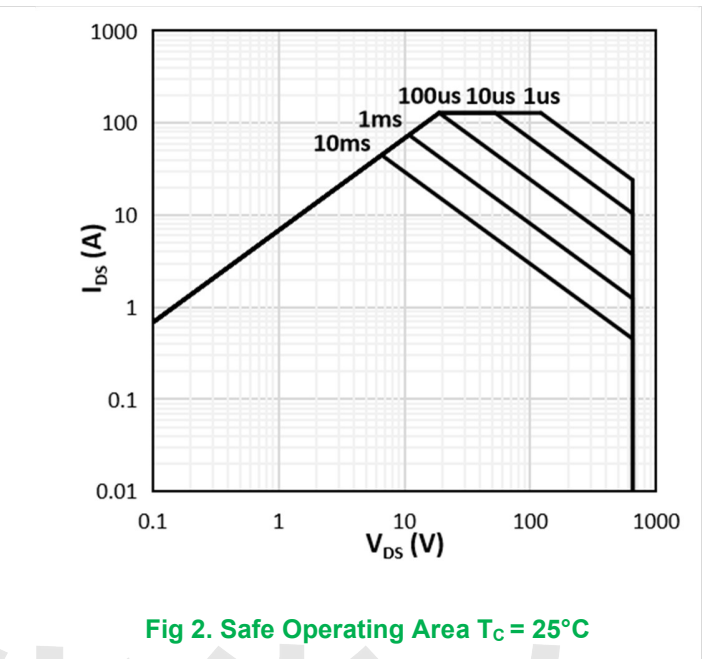


Fig 2. Safe Operating Area $T_c = 25^\circ\text{C}$

8. Thermal Characteristics

Table 5. Thermal Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Conditions
Thermal resistance (Junction-to-case)	$R_{th(j-c)}$	-	-	1.68	$^\circ\text{C} / \text{W}$	
Thermal resistance (Junction-to-ambient) ^a	$R_{th(j-a)}$	-	-	41	$^\circ\text{C} / \text{W}$	
Reflow soldering temperature	T_{SOLD}	-	-	260	$^\circ\text{C}$	Reflow MSL3

Notes:
 a. Device on one layer epoxy PCB for source connection (vertical and without air stream cooling, with 6cm² copper area and 70μm thickness).

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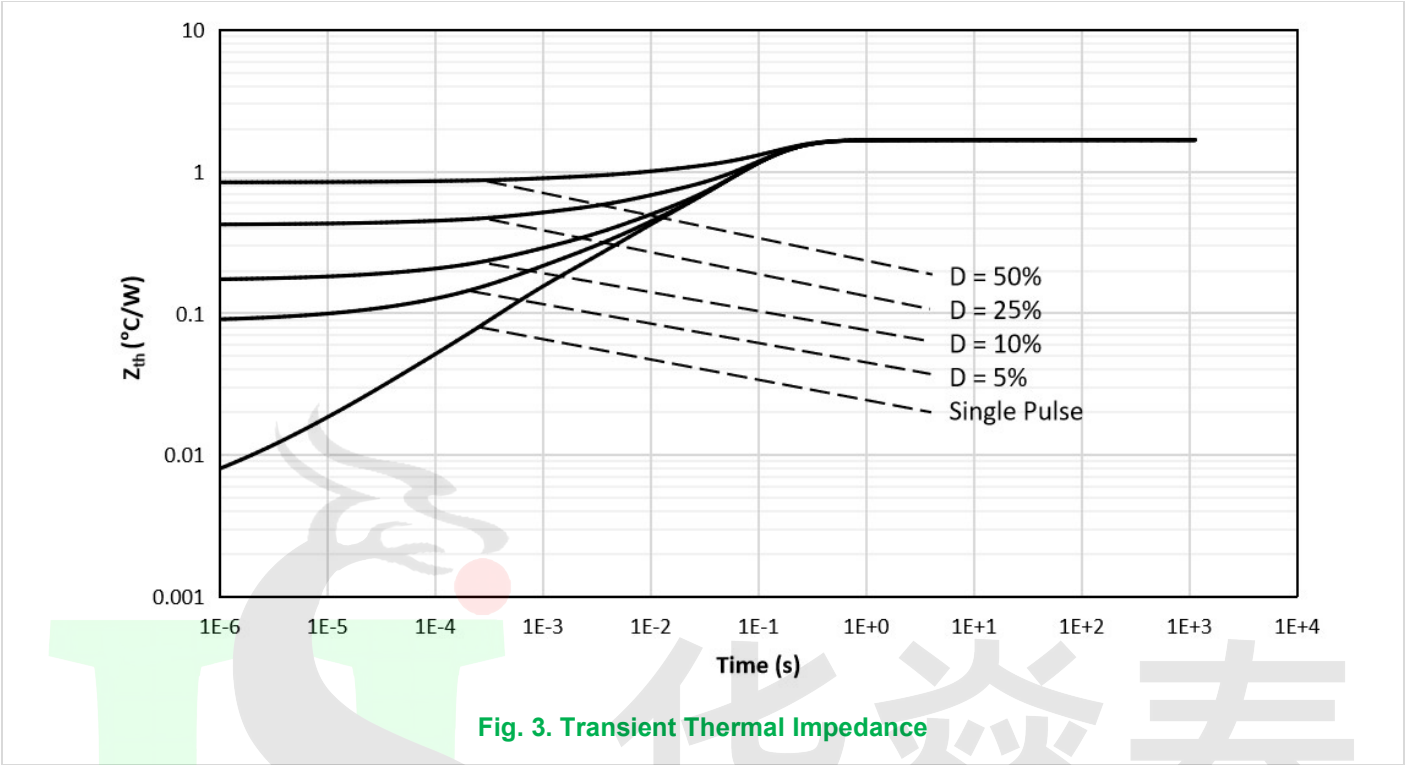


Fig. 3. Transient Thermal Impedance

9. Electrical Characteristics

Table 6. Electrical Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Conditions
Forward Device Characteristics						
Gate threshold voltage	V _{GS(th)}	3	3.8	4.6	V	V _{DS} = V _{GS} , I _D = 0.7mA, T _J = 25°C
		-	2.4	-		V _{DS} = V _{GS} , I _D = 0.7mA, T _J = 150°C
Drain-source on-state resistance ^b	R _{DS(on)}	-	70	87.5	mΩ	V _{GS} = 12V, I _D = 16A, T _J = 25°C, Fig.18 , Fig.19
		-	147	-		V _{GS} = 12V, I _D = 16A, T _J = 150°C, Fig.18 , Fig.19
Drain-to-source leakage current	I _{DSS}	-	5	25	μA	V _{DS} = 650V, V _{GS} = 0V, T _J = 25°C
		-	40	-		V _{DS} = 650V, V _{GS} = 0V, T _J = 150°C
Gate-to-source leakage current	I _{GSS}	-	-	100	nA	V _{GS} = 20V, V _{DS} = 0V, T _J = 25°C
		-	-	-100		V _{GS} = -20V, V _{DS} = 0V, T _J = 25°C

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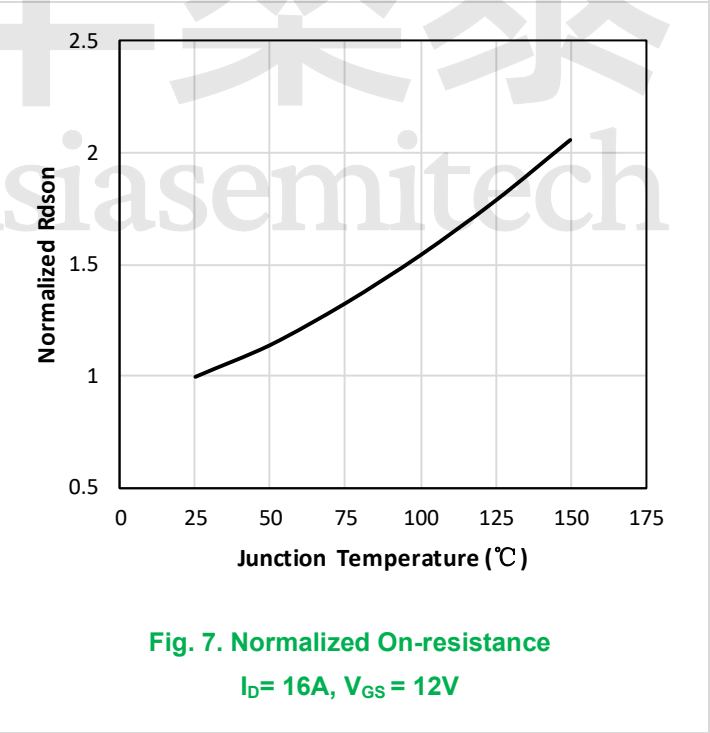
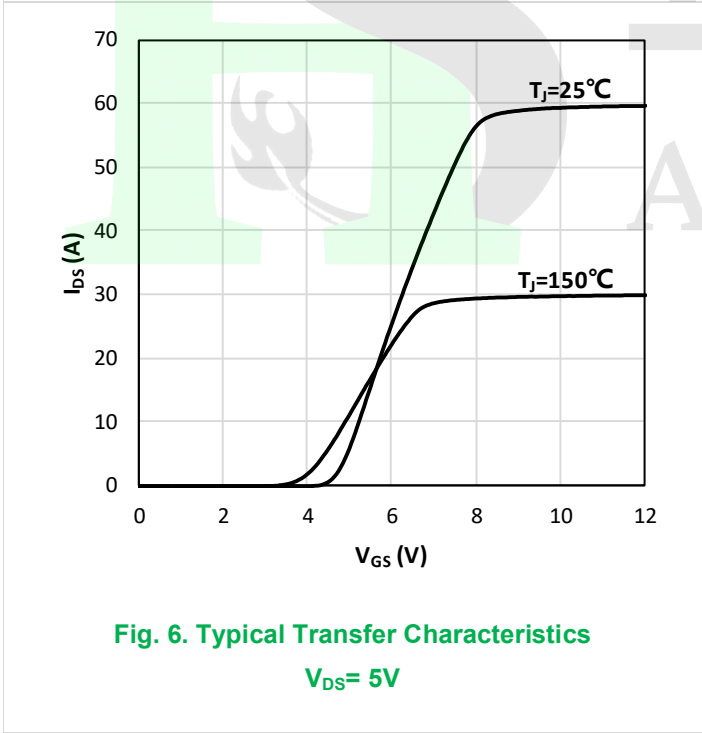
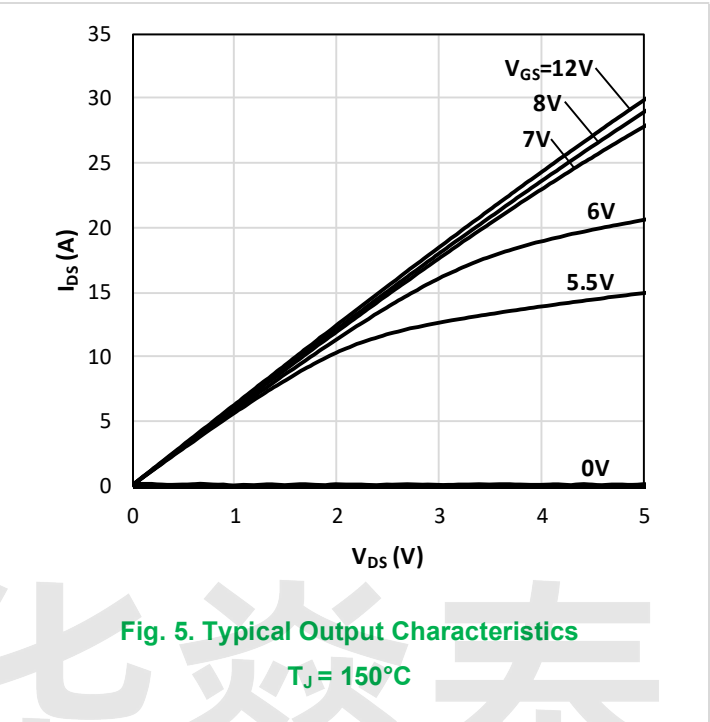
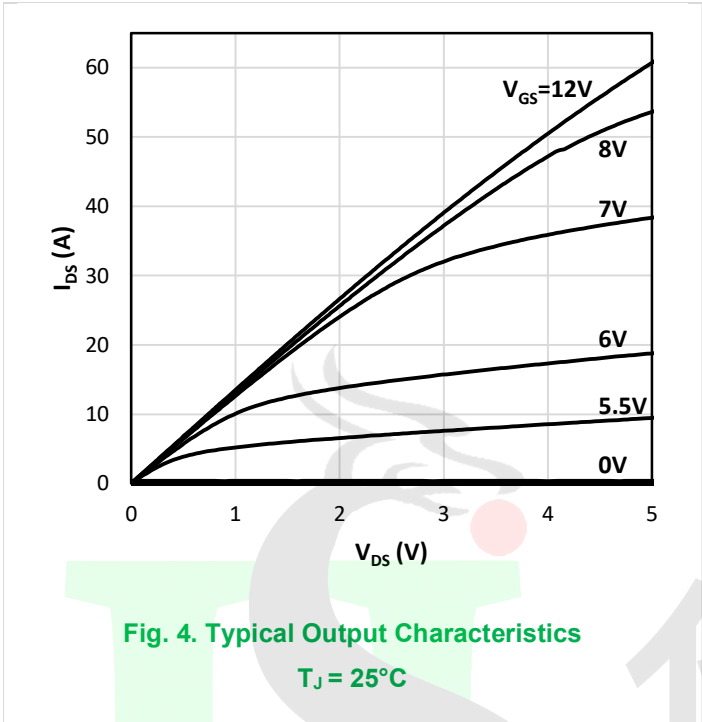
Parameter	Symbol	Min.	Typ.	Max.	Unit	Conditions
Input capacitance	C _{ISS}	-	770	-	pF	V _{GS} = 0V, V _{DS} = 400V, f = 1MHz, Fig.8
Output capacitance	C _{OSS}	-	71	-		
Reverse transfer capacitance	C _{RSS}	-	1.3	-		
Output capacitance, energy related ^c	C _{O(er)}	-	123	-	pF	V _{GS} = 0V, V _{DS} = 0V to 400V, Fig.9, Fig.10
Output capacitance, time related ^d	C _{O(tr)}	-	238	-		
Total gate charge	Q _G	-	15	-	nC	V _{DS} = 400V, V _{GS} = 0V to 12V, I _D = 16A, Fig.11
Gate-source charge	Q _{GS}	-	3.9	-		
Gate-drain charge	Q _{GD}	-	5.5	-		
Output charge	Q _{OSS}	-	95.3	-	nC	V _{GS} = 0V, V _{DS} = 0V to 400V
Turn-on delay	t _{D(on)}	-	32	-	ns	V _{DS} = 400V, V _{GS} = 0V to 12V, I _D = 16A, R _{G_on} = 51Ω, R _{G_off} = 2Ω, Fig.14, Fig.15
Rise time	t _R	-	16	-		
Turn-off delay	t _{D(off)}	-	30	-		
Fall time	t _F	-	7	-		
Reverse Device Characteristics						
Reverse voltage ^e	V _{SD}	-	2	-	V	V _{GS} = 0V, I _S = 16A, Fig.12
		-	1.4	-		V _{GS} = 0V, I _S = 8A, Fig.12
Reverse recovery time	t _{RR}	-	30	-	ns	I _S = 16A, V _{DD} = 400V, di/dt = 1000A/us, Fig.16, Fig.17
Reverse recovery charge	Q _{RR}	-	110	-	nC	

Notes:

- b. Dynamic $R_{DS(on)}$ value
- c. Equivalent capacitance to give same stored energy from 0V to 400V
- d. Equivalent capacitance to give same charging time from 0V to 400V
- e. Includes dynamic $R_{DS(on)}$ effect

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9.1 Electrical characteristics (curves) (T_c=25°C unless otherwise stated)



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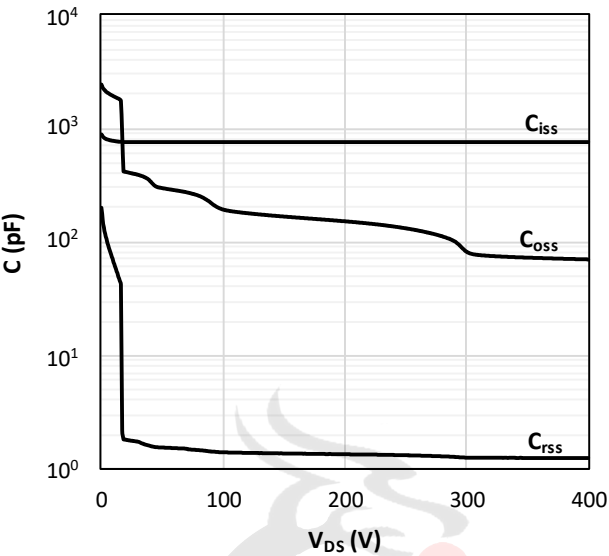


Fig. 8. Typical Capacitance
 $V_{GS} = 0V, f = 1MHz$

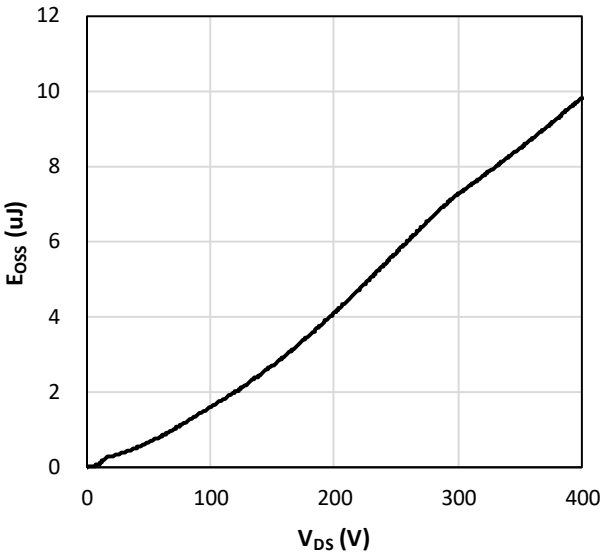


Fig. 9. Typical Coss Stored Energy
 $V_{GS} = 0V, f = 1MHz$

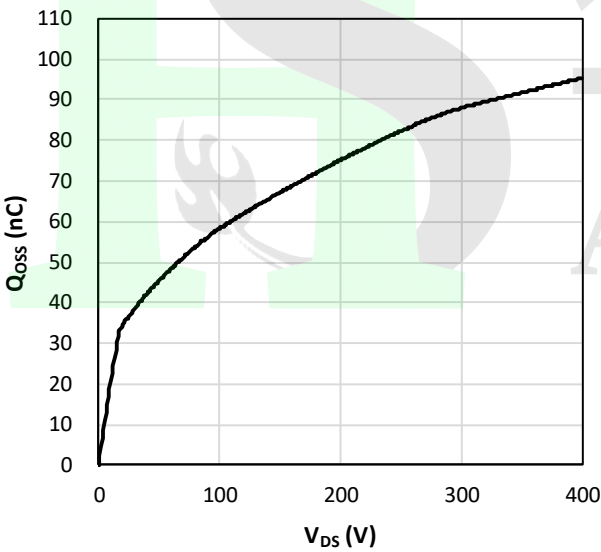


Fig. 10. Typical Q_{oss}

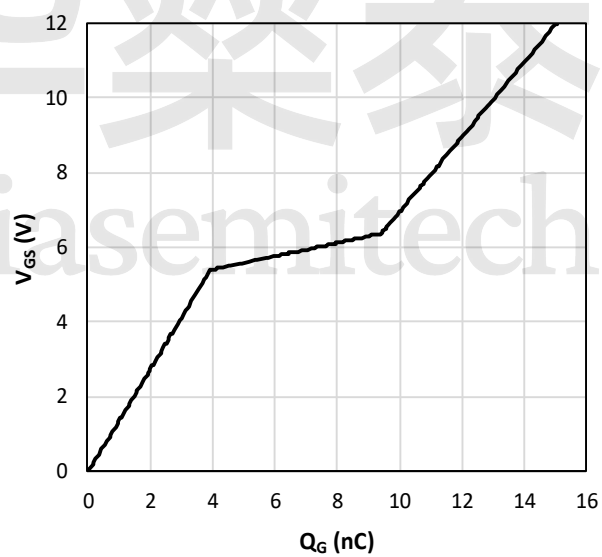


Fig. 11. Typical Gate Charge
 $I_{DS} = 16A, V_{DS} = 400V$

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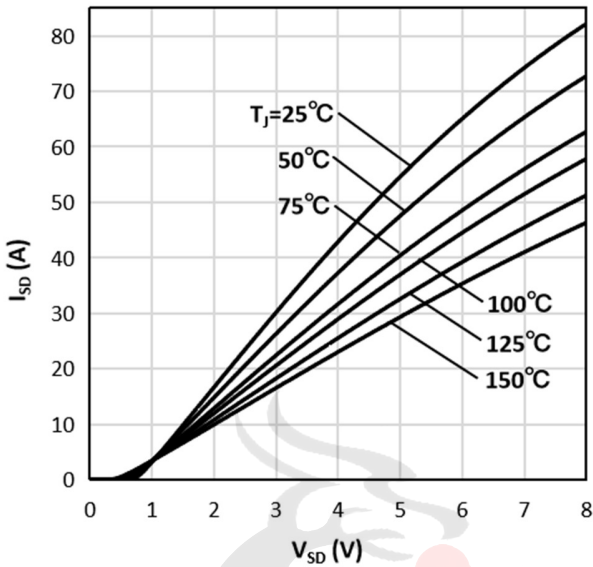


Fig. 12. Forward Characteristics of Rev. Diode

$I_{SD} = f(V_{SD})$

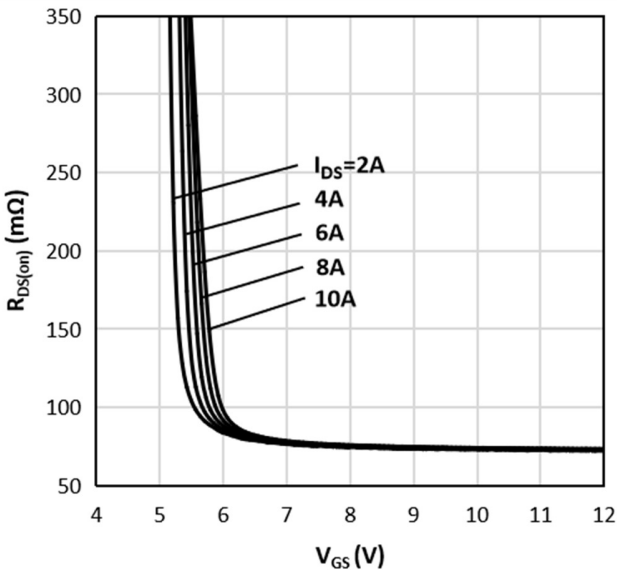


Fig. 13. Typical $R_{DS(on)}$

10. Test Circuits

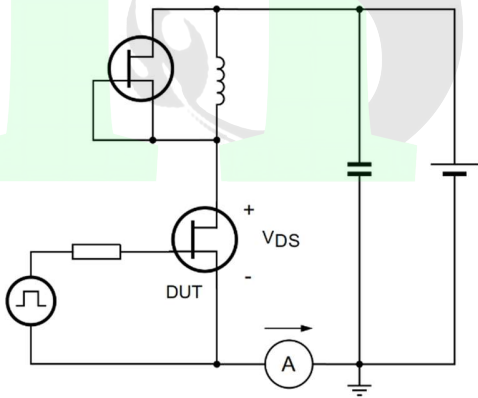


Fig. 14. Switching Time Test Circuit

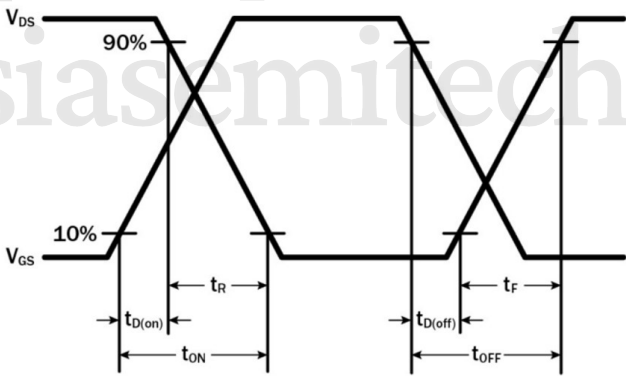


Fig. 15. Switching Time Waveform

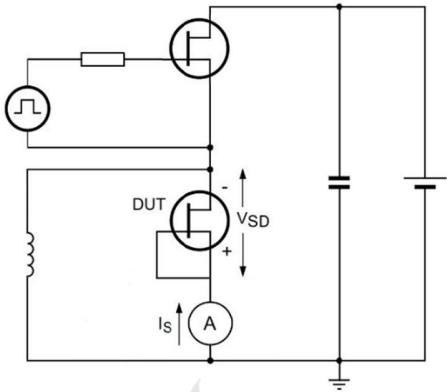


Fig. 16. Diode Characteristics Test Circuit

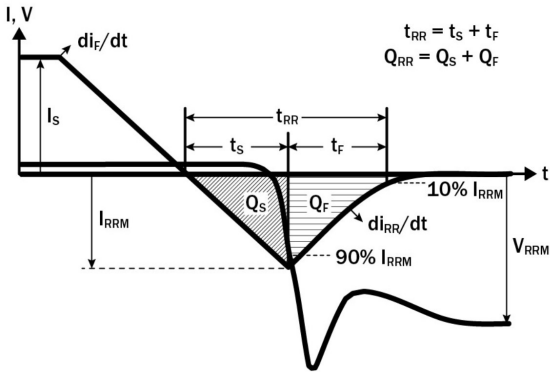


Fig. 17. Diode Recovery Waveform

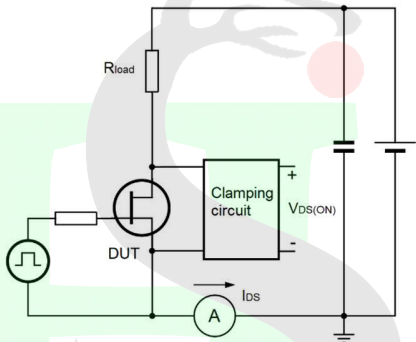


Fig. 18. Dynamic $R_{DS(on)eff}$ Test Circuit

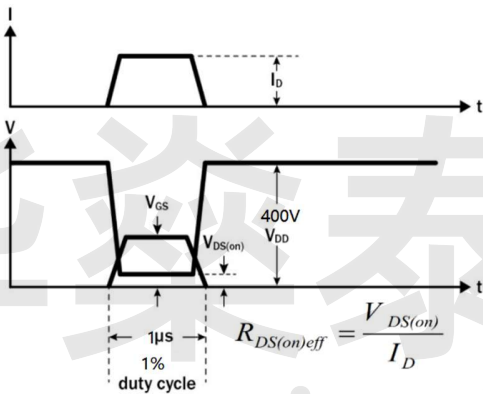


Fig. 19. Dynamic $R_{DS(on)eff}$ Waveform

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11. Package Information

11.1 TOLL Package Information

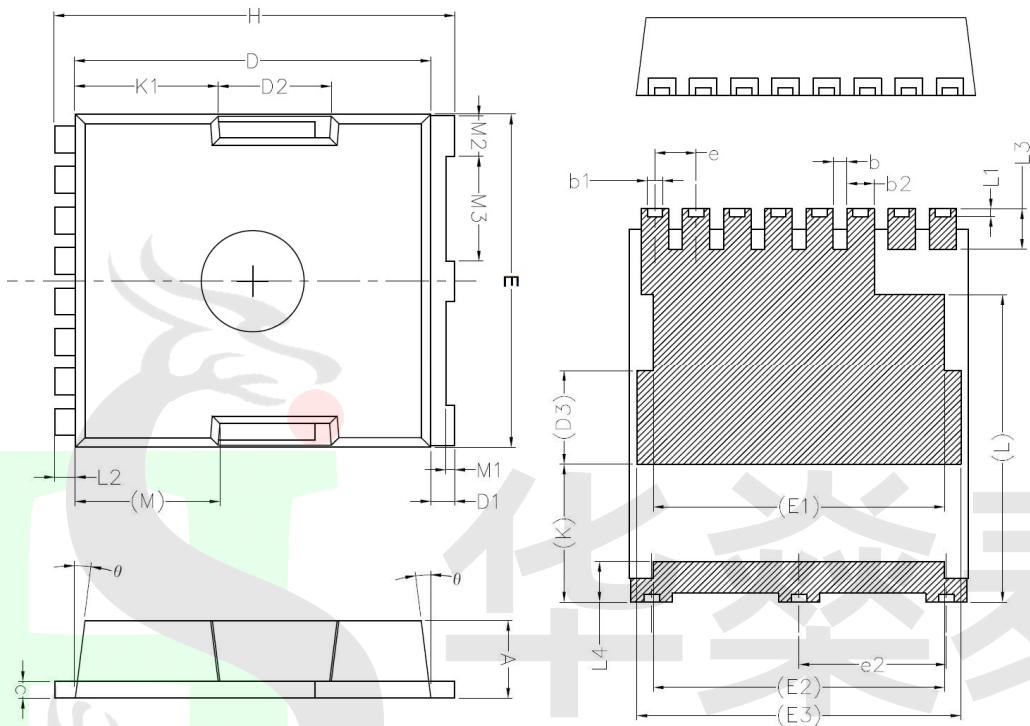


Fig. 20. TOLL Package Outline

SYMBOL	MIN	MAX	SYMBOL	MIN	MAX
A	2.20	2.40	H	11.48	11.88
b	0.30	0.50	K	(4.08)	
b1	0.35	0.55	K1	(4.17)	
b2	0.70	0.90	L	(9.13)	
c	0.40	0.60	L1	0.13	0.33
D	10.28	10.58	L2	0.50	0.70
D1	0.60	0.80	L3	1.10	1.30
D2	(3.30)		L4	1.10	1.30
D3	(2.77)		M	(4.23)	
E	9.70	10.10	M1	0.16	0.36
E1	(8.50)		M2	1.10	1.30
E2	(8.50)		M3	3.00	3.20
E3	(9.46)		θ	4°	10°
e	1.10	1.30	e2	4.20	4.40

12. Important Notice

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Revision History

Revision	Date	Changes
1.0	25/09/2023	Release Preliminary Datasheet
1.1	22/01/2024	Preliminary Datasheet $R_{DS(on)}$ updated
1.2	09/05/2025	Preliminary Datasheet P_D, I_D, I_{DM} updated